

SILICON POWER TRANSISTOR 2SC4815

NPN SILICON EPITAXIAL TRANSISTOR FOR HIGH-SPEED SWITCHING

The 2SC4815 is a power transistor developed for high-speed switching and features low VcE(sat) and high here. This transistor is ideal for use as a driver in DC/DC converters and actuators.

In addition, this transistor is available for the auto mount in the radial taping specifications and for mounting cost reduction.

FEATURES

• High hre and low VCE(sat):

 $V_{CE(sat)} \le 0.3 \text{ V}$ @ Ic = 3.0 A, IB = 0.15 A $h_{FE} \ge 100$ @ $V_{CE} = 2.0 \text{ V}$, Ic = 1.0 A

· Available for auto mount in radial taping specifications

ABSOLUTE MAXIMUM RATINGS (Ta = 25°C)

| Parameter | Symbol | Ratings | Unit |
|------------------------------|--------------------|-------------|------|
| Collector to base voltage | Vсво | 100 | V |
| Collector to emitter voltage | Vceo | 60 | V |
| Emitter to base voltage | VEBO | 7.0 | ٧ |
| Collector current (DC) | Ic(DC) | 5.0 | Α |
| Collector current (pulse) | Ic(pulse)* | 10 | Α |
| Base current (DC) | I _{B(DC)} | 2.5 | Α |
| Total power dissipation | Рт | 1.8 | W |
| Junction temperature | Tj | 150 | °C |
| Storage temperature | T _{stg} | -55 to +150 | °C |

^{*} PW \leq 300 μ s, duty cycle \leq 10%

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ELECTRICAL CHARACTERISTICS (Ta = 25°C)

| Parameter | Symbol | Conditions | MIN. | TYP. | MAX. | Unit |
|------------------------------|-------------------------|---|------|------|------|------|
| Collector to emitter voltage | VCEO(SUS) | Ic = 5.0 A, Iв = 0.5 A, L = 1 mH | 60 | | | ٧ |
| Collector to emitter voltage | VCEX(SUS) | Ic = 2.5 A, I _{B1} = $-I_{B2}$ = 0.25 A V _{BE(OFF)} = -1.5 V, L = 180 μ H, Clamped | 60 | | | V |
| Collector cutoff current | Ісво | Vcb = 100 V, IE = 0 | | | 10 | μΑ |
| Emitter cutoff current | Ієво | V _{EB} = 7.0 V, I _C = 0 | | | 10 | μΑ |
| DC current gain | h _{FE1} * | Vce = 2.0 V, Ic = 0.5 A | 100 | | | |
| DC current gain | h _{FE2} * | Vce = 2.0 V, Ic = 1.0 A | 100 | 200 | 400 | |
| DC current gain | h _{FE3} * | Vce = 2.0 V, Ic = 3.0 A | 60 | | | |
| Collector saturation voltage | V _{CE(sat)1} * | Ic = 3.0 A, Iв = 0.15 A | | 0.15 | 0.3 | ٧ |
| Collector saturation voltage | V _{CE(sat)2} * | Ic = 4.0 A, I _B = 0.2 A | | 0.3 | 0.5 | ٧ |
| Base saturation voltage | V _{BE(sat)1} * | Ic = 3.0 A, Iв = 0.15 A | | 0.9 | 1.2 | ٧ |
| Base saturation voltage | V _{BE(sat)2} * | Ic = 4.0 A, I _B = 0.2 A | | 1.2 | 1.5 | ٧ |
| Collector capacitance | Соь | Vcb = 10 V, IE = 0 , f = 1.0 MHz | | 70 | | pF |
| Gain bandwidth product | f⊤ | Vce = 10 V, Ic = 0.5 A | | 150 | | MHz |
| Turn-on time | ton | Ic = 3.0 A, R _L = 17 Ω , | | 0.1 | | μs |
| Storage time | tstg | $I_{B1} = -I_{B2} = 0.15 \text{ A}, V_{CC} \cong 50 \text{ V}$ Refer to the test circuit. | | 1.0 | | μs |
| Fall time | tf | neier to the test circuit. | | 0.25 | | μs |

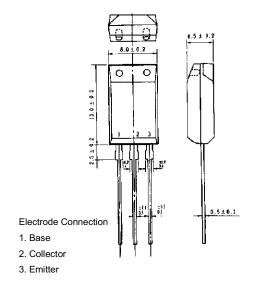
^{*} Pulse test PW \leq 350 μ s, duty cycle \leq 2%

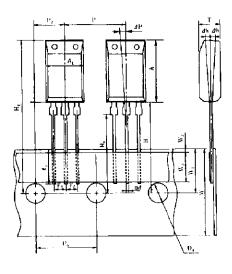
hfe CLASSIFICATION

| Marking | М | L | К | |
|------------------|------------|------------|------------|--|
| h _{FE2} | 100 to 200 | 150 to 300 | 200 to 400 | |

PACKAGE DRAWING (UNIT: mm)

TAPING SPECIFICATION

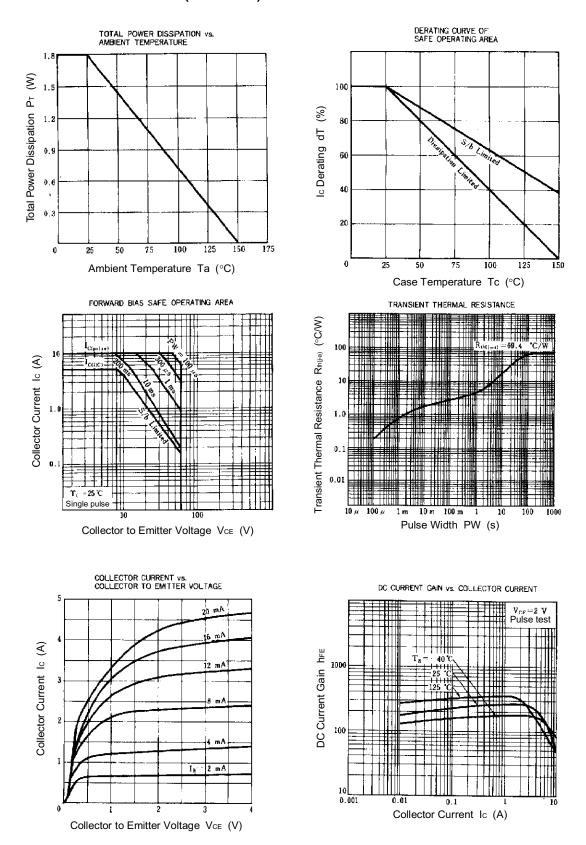




| A_1 | 8.0±0.2 |
|------------------|-------------|
| A | 13.0±0.2 |
| D_0 | Ø4.0±0.2 |
| d | 0.5±0.1 |
| \mathbf{F}_1 | 2.5.0.4 |
| \mathbf{F}_{z} | 2.5-0.1 |
| H | 20.0 MAX. |
| Ho | 16.0±0.5 |
| $\mathbf{H_1}$ | 32.2 MAX. |
| ⊿h | 0±1.0 |
| Ł ₁ | 2.5 MIN. |
| P | 12.7 ± 1.0 |
| P_0 | 12.7 ± 0.3 |
| P_2 | 6.35±0.5 |
| ΔP | 0±1.3 |
| T | 4.5±0.2 |
| W | 18.0+1.0 |
| W ₀ | 5.0 MIN. |
| \mathbf{W}_1 | 9.0±0.5 |
| W ₂ | 0.7 or less |
| | <u></u> |

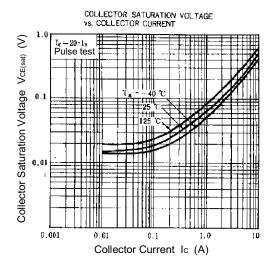


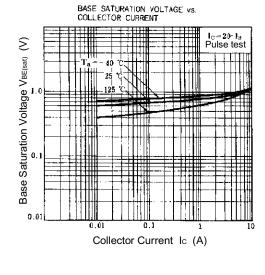
TYPICAL CHARACTERISTICS (Ta = 25°C)

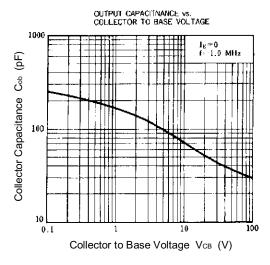


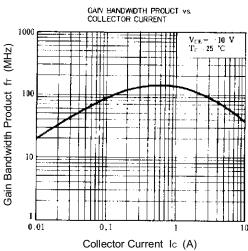
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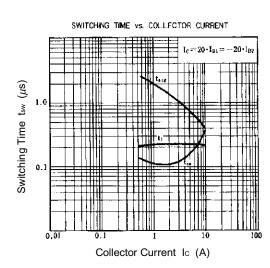
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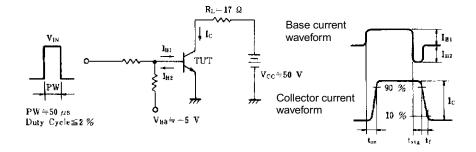








SWITCHING TIME (ton, tstg, tf) TEST CIRCUIT



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